
FINAL PRODUCT/PROCESS CHANGE NOTIFICATION
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31 Jan 2008

SUBJECT: ON Semiconductor Final Product/Process Change Notification #16094

TITLE: Final Qualification of AIT, Batam, Indonesia for Assembly/Test of LQFP 52/64 LD EP

PROPOSED FIRST SHIP DATE: 01-May-2008

AFFECTED CHANGE CATEGORY(S): Subcontractor Assembly/Test Site

AFFECTED PRODUCT DIVISION(S): Standard Products

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor Sales Office or Gregg Hooker <gregg.hooker@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available
Contact your local ON Semiconductor Sales Office or Matt Kas <Matt.Kas@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

This is the FPCN to IPCN 160371 available at www.onsemi.com. This is the Final Product Change Notice to advise customers of the completed qualification of formerly AIT (Advanced Interconnect Technologies) now called UNISEM to assemble and test at OSPI the LQFP 52/64 lead exposed pad package. This is additional capacity to supplement the current assembly site at ASE located in Taiwan. AIT is QS9000, ISO9002 and TS16949 certified. UNISEM is qualified and currently assembling other packages for ON Semiconductor.

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RELIABILITY DATA SUMMARY:

Reliability Test Results:
Qualification Vehicles: **NB100LVEP224FAG (LQFP 64EP), NB100LVEP221FAG (LQFP 52EP)**

		LVEP224 (LQFP 64EP)			LVEP221 (LQFP 52EP)		
Test	Conditions	# Lots	Samples	Results	# Lots	Samples	Results
HSTL	Ta/min 150C for 1008 Hrs	2	160	0/160	1	80	0/80
AC	121C, 100%RH, 15PSIG 96 Hrs	2	160	0/160	1	80	0/80
UHAST	131C, 85%RH, 96 Hrs	2	160	0/160	1	80	0/80
TC	-65C to +150C, 500Cyc	2	160	0/160	1	80	0/80
SAT		2	160	Pass	1	80	Pass

ELECTRICAL CHARACTERISTIC SUMMARY:

Characterization data available upon request.

CHANGED PART IDENTIFICATION:

All 52/64 Ld Exposed Pad devices with a date code including and after 0818 represent devices that are potentially assembled at UNISEM.

AFFECTED DEVICE LIST

MC100LVE222FA
MC100LVE222FAG
MC100LVE222FAR2
MC100LVE222FAR2G
NB100LVEP221FA
NB100LVEP221FAG
NB100LVEP221FAR2
NB100LVEP221FARG
NB100LVEP222FA
NB100LVEP222FAG
NB100LVEP222FAR2
NB100LVEP222FAR2G
NB100EP223FA
NB100EP223FAG
NB100EP223FAR2
NB100EP223FAR2G
NB100LVEP224FA
NB100LVEP224FAG
NB100LVEP224FAR2